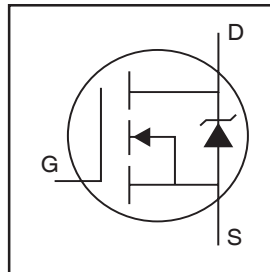# International IOR Rectifier

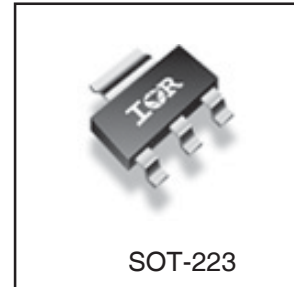# IRFL024ZPbF

HEXFET® Power MOSFET

Features
- Advanced Process Technology
- Ultra Low On-Resistance
- 150°C Operating Temperature
- Fast Switching
- Repetitive Avalanche Allowed up to Tjmax
- Lead-Free

Description
This HEXFET® Power MOSFET utilizes the latest processing techniques to achieve extremely low on-resistance per silicon area. Additional features of this design are a 150°C junction operating temperature, fast switching speed and improved repetitive avalanche rating . These features combine to make this design an extremely efficient and reliable device for use in a wide variety of applications.

$V_{DSS} = 55V$

$R_{DS(on)} = 57.5m\Omega$

$I_D = 5.1A$

SOT-223

Absolute Maximum Ratings

	Parameter	Max.	Units
I_D @ $T_A = 25°C$	Continuous Drain Current, V_{GS} @ 10V (Silicon Limited) [7]	5.1	A
I_D @ $T_A = 70°C$	Continuous Drain Current, V_{GS} @ 10V [7]	4.1	
I_{DM}	Pulsed Drain Current [1]	41	
P_D @$T_A = 25°C$	Power Dissipation [7]	2.8	
P_D @$T_A = 25°C$	Power Dissipation [8]	1.0	W
	Linear Derating Factor [7]	0.02	W/°C
V_{GS}	Gate-to-Source Voltage	± 20	V
$E_{AS (Thermally limited)}$	Single Pulse Avalanche Energy[2]	13	mJ
E_{AS} (Tested)	Single Pulse Avalanche Energy Tested Value [6]	32	
I_{AR}	Avalanche Current [1]	See Fig.12a, 12b, 15, 16	A
E_{AR}	Repetitive Avalanche Energy [5]		mJ
T_J	Operating Junction and	-55 to + 150	
T_{STG}	Storage Temperature Range		°C

Thermal Resistance

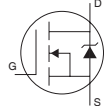|	Parameter	Typ.	Max.	Units
$R_{\theta JA}$	Junction-to-Ambient (PCB mount, steady state) [7]	——	45	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mount, steady state) [8]	——	120	

International IQR Rectifier

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	55	—	—	V	V_{GS} = 0V, I_D = 250µA
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.053	—	V/°C	Reference to 25°C, I_D = 1mA
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	46.2	57.5	mΩ	V_{GS} = 10V, I_D = 3.1A ③
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	4.0	V	V_{DS} = V_{GS}, I_D = 250µA
gfs	Forward Transconductance	6.2	—	—	S	V_{DS} = 25V, I_D = 3.1A
I_{DSS}	Drain-to-Source Leakage Current	—	—	20	µA	V_{DS} = 55V, V_{GS} = 0V
		—	—	250		V_{DS} = 55V, V_{GS} = 0V, T_J = 125°C
I_{GSS}	Gate-to-Source Forward Leakage	—	—	200	nA	V_{GS} = 20V
	Gate-to-Source Reverse Leakage	—	—	-200		V_{GS} = -20V
Q_g	Total Gate Charge	—	9.1	14		I_D = 3.1A
Q_{gs}	Gate-to-Source Charge	—	1.9	—	nC	V_{DS} = 44V
Q_{gd}	Gate-to-Drain ("Miller") Charge	—	3.9	—		V_{GS} = 10V ③
$t_{d(on)}$	Turn-On Delay Time	—	7.8	—		V_{DD} = 28V
t_r	Rise Time	—	21	—	ns	I_D = 3.1A
$t_{d(off)}$	Turn-Off Delay Time	—	30	—		R_G = 53 Ω
t_f	Fall Time	—	23	—		V_{GS} = 10V ③
C_{iss}	Input Capacitance	—	340	—		V_{GS} = 0V
C_{oss}	Output Capacitance	—	68	—		V_{DS} = 25V
C_{rss}	Reverse Transfer Capacitance	—	39	—	pF	f = 1.0MHz
C_{oss}	Output Capacitance	—	210	—		V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0MHz
C_{oss}	Output Capacitance	—	55	—		V_{GS} = 0V, V_{DS} = 44V, f = 1.0MHz
C_{oss} eff.	Effective Output Capacitance	—	93	—		V_{GS} = 0V, V_{DS} = 0V to 44V ④

Source-Drain Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Conditions
I_S	Continuous Source Current (Body Diode)	—	—	5.1	A	MOSFET symbol showing the integral reverse p-n junction diode.
I_{SM}	Pulsed Source Current (Body Diode) ①	—	—	41		
V_{SD}	Diode Forward Voltage	—	—	1.3	V	T_J = 25°C, I_S = 3.1A, V_{GS} = 0V ③
t_{rr}	Reverse Recovery Time	—	15	23	ns	T_J = 25°C, I_F = 3.1A, V_{DD} = 28V
Q_{rr}	Reverse Recovery Charge	—	9.8	15	nC	di/dt = 100A/µs ③
t_{on}	Forward Turn-On Time		Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)			

Notes:

① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).

② Limited by T_{Jmax}, starting T_J = 25°C, L = 2.8mH R_G = 25Ω, I_{AS} = 3.1A, V_{GS} =10V. Part not recommended for use above this value.

③ Pulse width ≤ 1.0ms; duty cycle ≤ 2%.

④ C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80% V_{DSS}.

⑤ Limited by T_{Jmax} , see Fig.12a, 12b, 15, 16 for typical repetitive avalanche performance.

⑥ This value determined from sample failure population. 100% tested to this value in production.

⑦ When mounted on 1 inch square copper board.

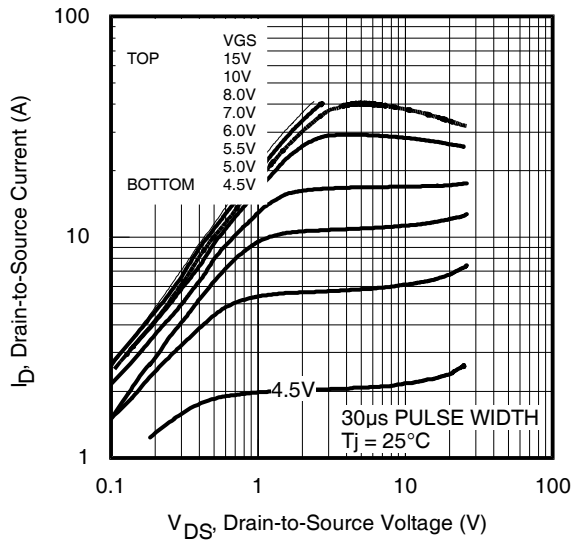⑧ When mounted on FR-4 board using minimum recommended footprint.

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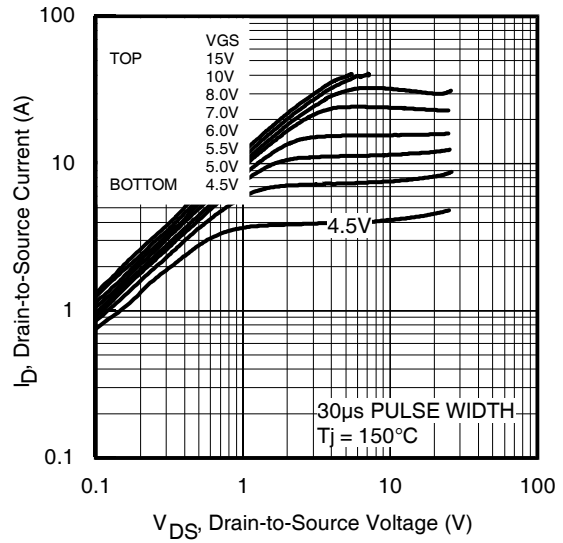**Fig 1.** Typical Output Characteristics
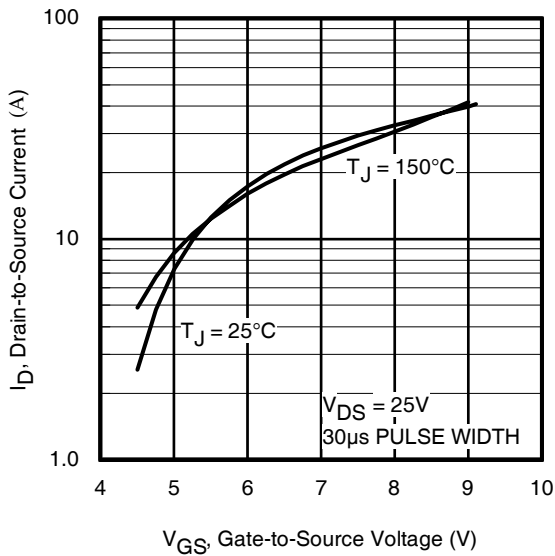

Fig 2. Typical Output Characteristics
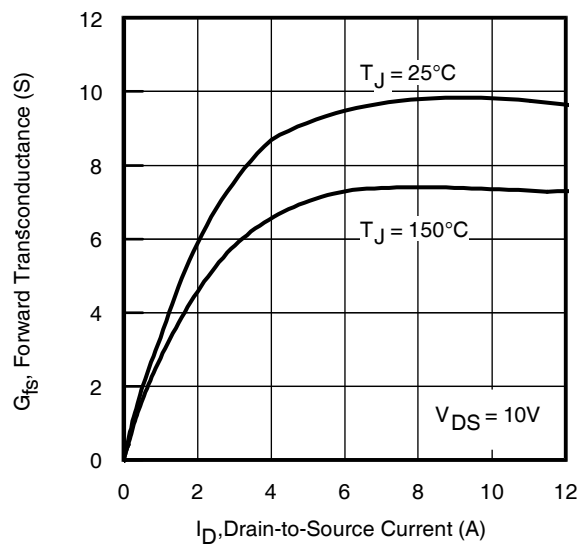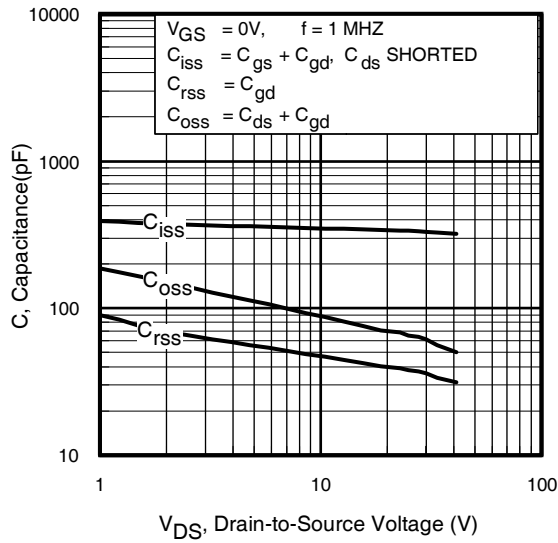

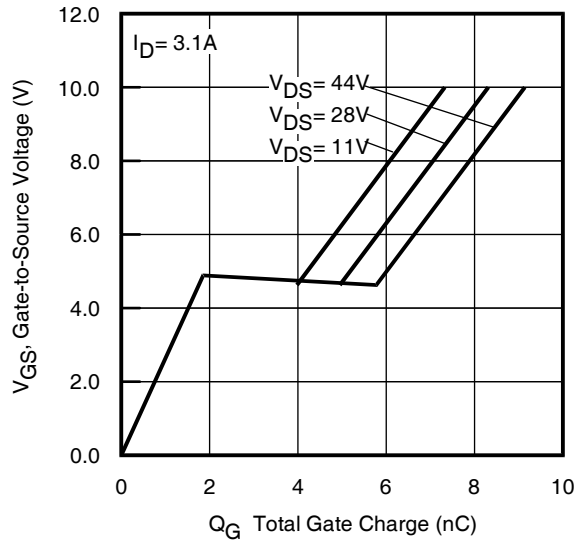**Fig 3.** Typical Transfer Characteristics

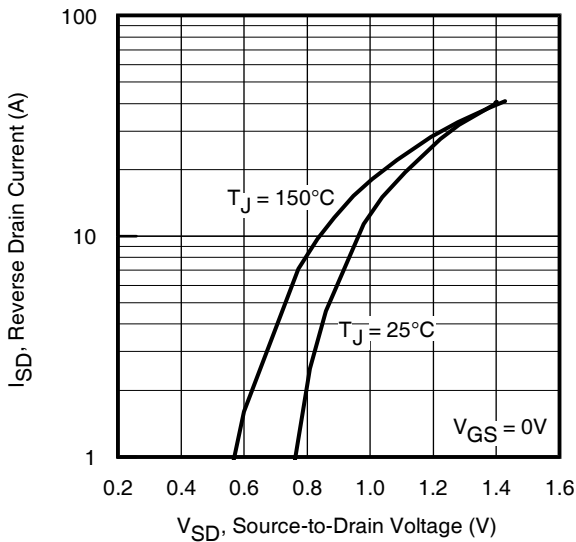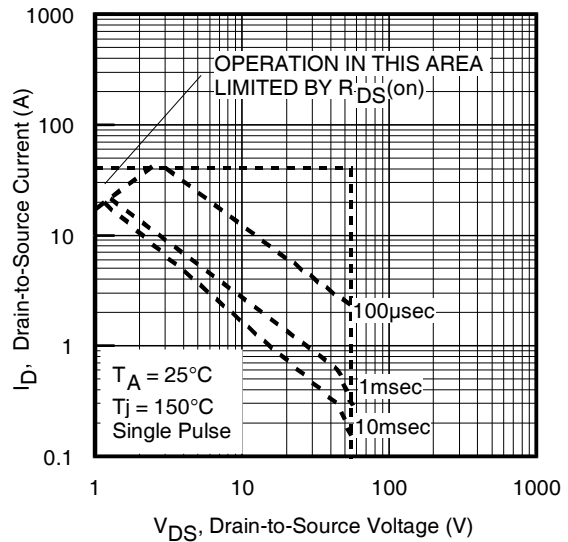**Fig 4.** Typical Forward Transconductance vs. Drain Current

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Fig 5. Typical Capacitance vs.
Drain-to-Source Voltage

$V_{GS} = 0V$, $f = 1\ MHZ$
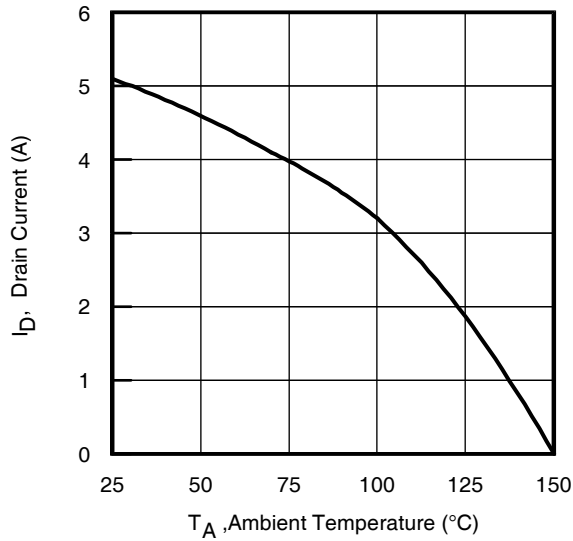$C_{iss} = C_{gs} + C_{gd}$, C_{ds} SHORTED
$C_{rss} = C_{gd}$
$C_{oss} = C_{ds} + C_{gd}$

C, Capacitance(pF)

C_{iss}
C_{oss}
C_{rss}

V_{DS}, Drain-to-Source Voltage (V)

Fig 6. Typical Gate Charge vs.
Gate-to-Source Voltage

$I_D = 3.1A$

V_{GS}, Gate-to-Source Voltage (V)

$V_{DS}= 44V$
$V_{DS}= 28V$
$V_{DS}= 11V$

Q_G Total Gate Charge (nC)

Fig 7. Typical Source-Drain Diode
Forward Voltage

I_{SD}, Reverse Drain Current (A)

$T_J = 150°C$

$T_J = 25°C$

$V_{GS} = 0V$

V_{SD}, Source-to-Drain Voltage (V)

Fig 8. Maximum Safe Operating Area

I_D, Drain-to-Source Current (A)

OPERATION IN THIS AREA
LIMITED BY R_{DS}(on)

100µsec
1msec
10msec

$T_A = 25°C$
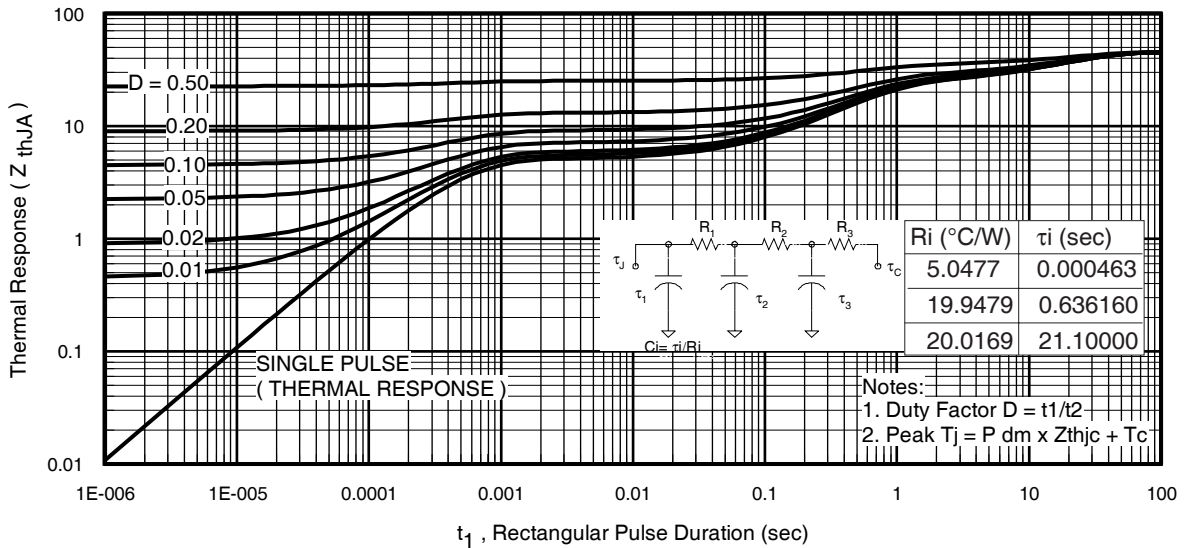$T_j = 150°C$
Single Pulse

V_{DS}, Drain-to-Source Voltage (V)

4

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Fig 9. Maximum Drain Current vs.
Ambient Temperature

Fig 10. Normalized On-Resistance
vs. Temperature

Ri (°C/W)	τi (sec)
5.0477	0.000463
19.9479	0.636160
20.0169	21.10000

SINGLE PULSE
(THERMAL RESPONSE)

Notes:
1. Duty Factor D = t1/t2
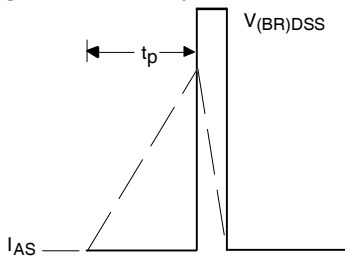2. Peak Tj = P dm x Zthjc + Tc

$C_i = \tau i / R i$

Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Ambient
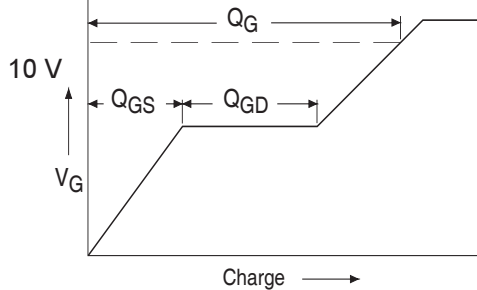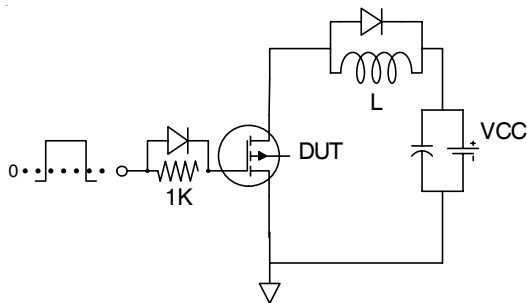
IRFL024ZPbF

Fig 12a. Unclamped Inductive Test Circuit
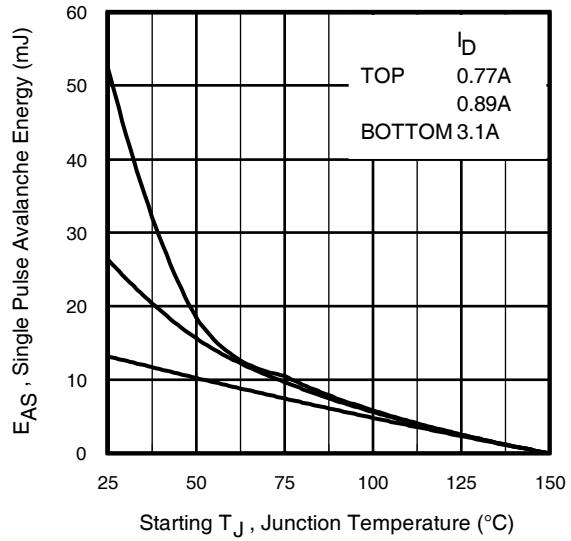

Fig 12b. Unclamped Inductive Waveforms

Fig 13a. Basic Gate Charge Waveform

Fig 13b. Gate Charge Test Circuit
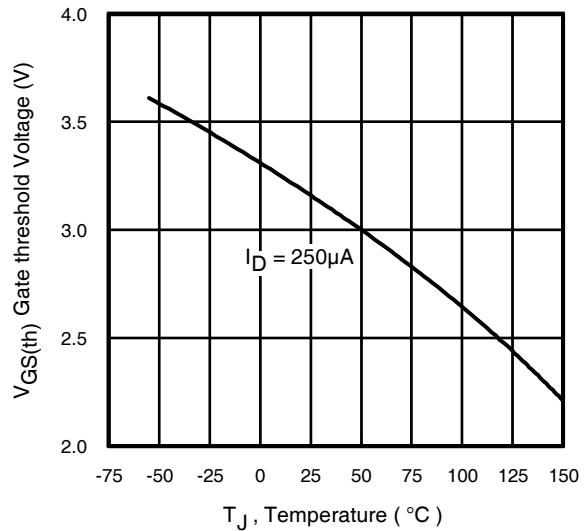

I_D
TOP   0.77A
            0.89A
BOTTOM 3.1A

Fig 12c. Maximum Avalanche Energy
vs. Drain Current

$I_D = 250\mu A$

Fig 14. Threshold Voltage vs. Temperature

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Fig 15. Typical Avalanche Current vs.Pulsewidth

Duty Cycle = Single Pulse

Allowed avalanche Current vs avalanche pulsewidth, tav assuming $\Delta T_j = 25°C$ due to avalanche losses

TOP Single Pulse
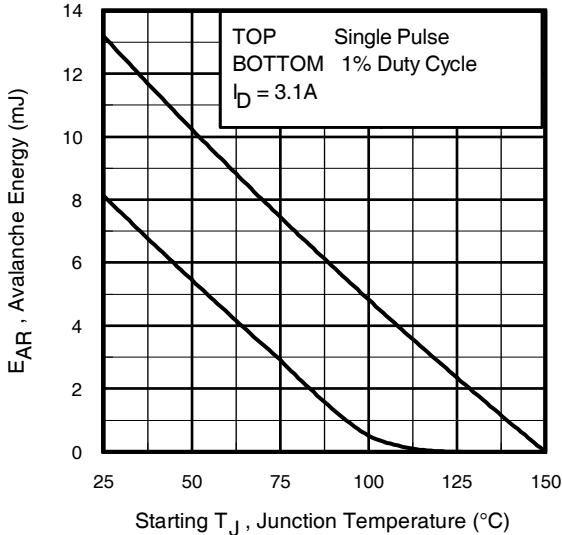BOTTOM 1% Duty Cycle
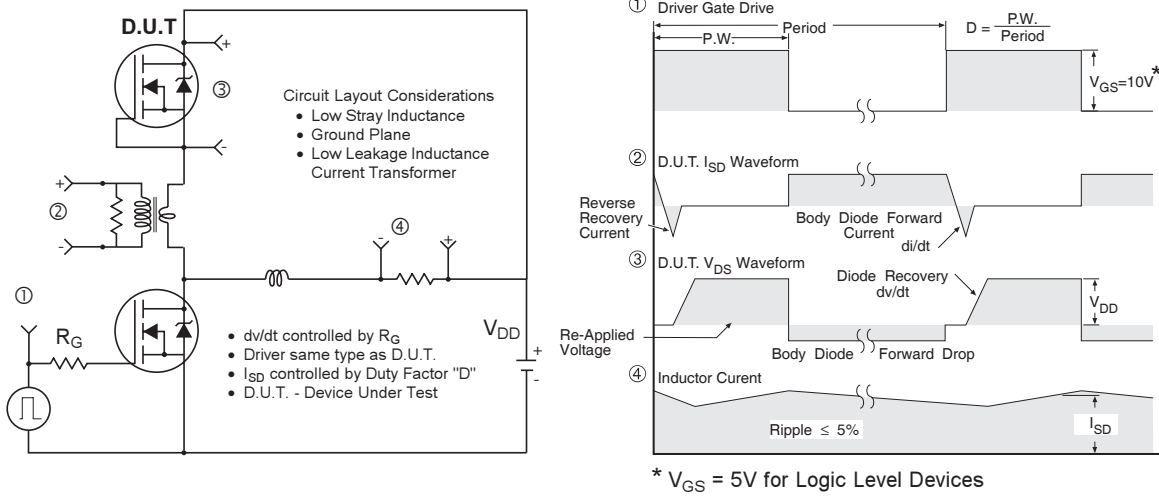$I_D = 3.1A$

Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16:
(For further info, see AN-1005 at www.irf.com)
1. Avalanche failures assumption:
   Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
2. Safe operation in Avalanche is allowed as long as T_{jmax} is not exceeded.
3. Equation below based on circuit and waveforms shown in Figures 12a, 12b.
4. $P_{D\ (ave)}$ = Average power dissipation per single avalanche pulse.
5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
6. I_{av} = Allowable avalanche current.
7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16).
   t_{av} = Average time in avalanche.
   D = Duty cycle in avalanche = $t_{av} \cdot f$
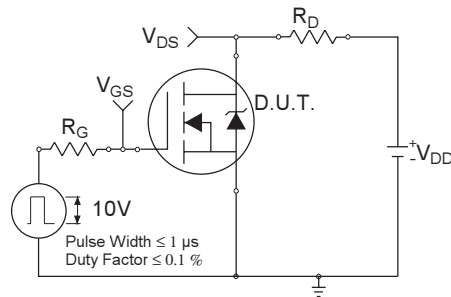 $Z_{thJC}(D, t_{av})$ = Transient thermal resistance, see figure 11)

$$P_{D\ (ave)} = 1/2\ (\ 1.3 \cdot BV \cdot I_{av}) = \Delta T/\ Z_{thJC}$$
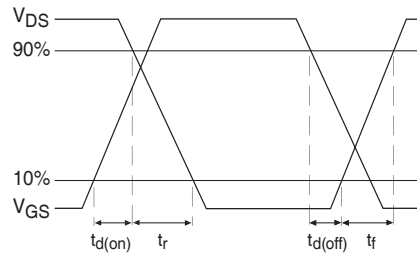$$I_{av} = 2\Delta T/\ [1.3 \cdot BV \cdot Z_{th}]$$
$$E_{AS\ (AR)} = P_{D\ (ave)} \cdot t_{av}$$

Fig 17. Peak Diode Recovery dv/dt Test Circuit for N-Channel
HEXFET® Power MOSFETs

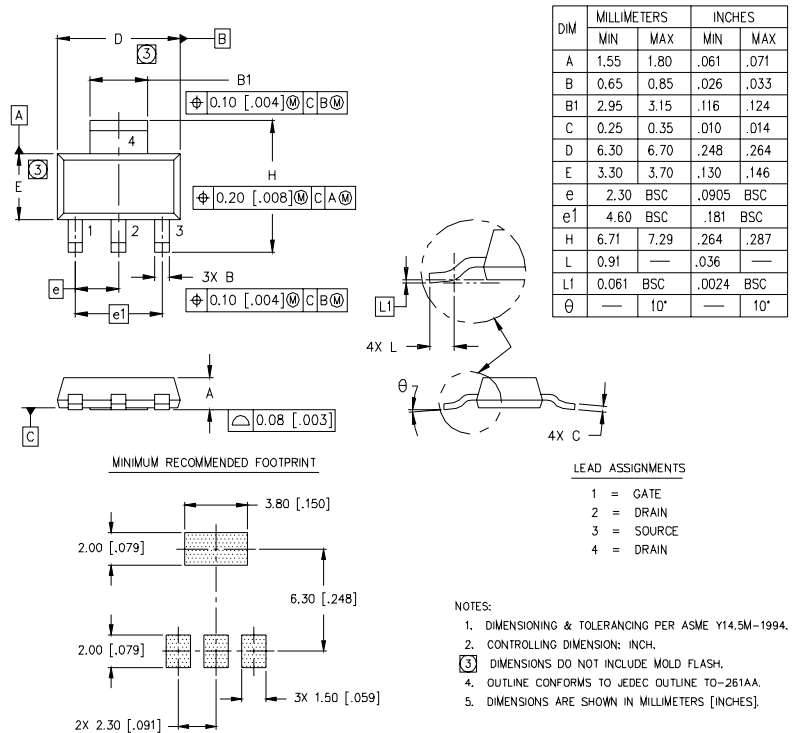**Fig 18a.** Switching Time Test Circuit

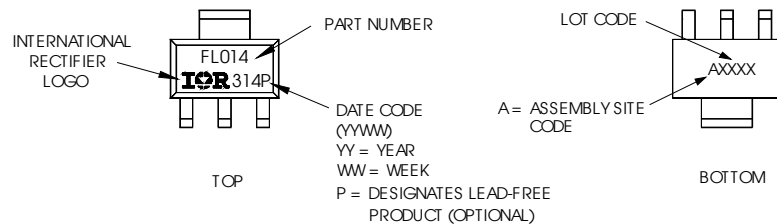**Fig 18b.** Switching Time Waveforms

SOT-223 (TO-261AA) Package Outline

Dimensions are shown in milimeters (inches)

DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	1.55	1.80	.061	.071
B	0.65	0.85	.026	.033
B1	2.95	3.15	.116	.124
C	0.25	0.35	.010	.014
D	6.30	6.70	.248	.264
E	3.30	3.70	.130	.146
e	2.30	BSC	.0905	BSC
e1	4.60	BSC	.181	BSC
H	6.71	7.29	.264	.287
L	0.91	—	.036	—
L1	0.061	BSC	.0024	BSC
θ	—	10°	—	10°

MINIMUM RECOMMENDED FOOTPRINT

3.80 [.150]
2.00 [.079]
6.30 [.248]
2.00 [.079]
3X 1.50 [.059]
2X 2.30 [.091]

LEAD ASSIGNMENTS
1 = GATE
2 = DRAIN
3 = SOURCE
4 = DRAIN

NOTES:
1. DIMENSIONING & TOLERANCING PER ASME Y14.5M-1994.
2. CONTROLLING DIMENSION: INCH.
3. DIMENSIONS DO NOT INCLUDE MOLD FLASH.
4. OUTLINE CONFORMS TO JEDEC OUTLINE TO-261AA.
5. DIMENSIONS ARE SHOWN IN MILLIMETERS [INCHES].

SOT-223 (TO-261AA) Part Marking Information

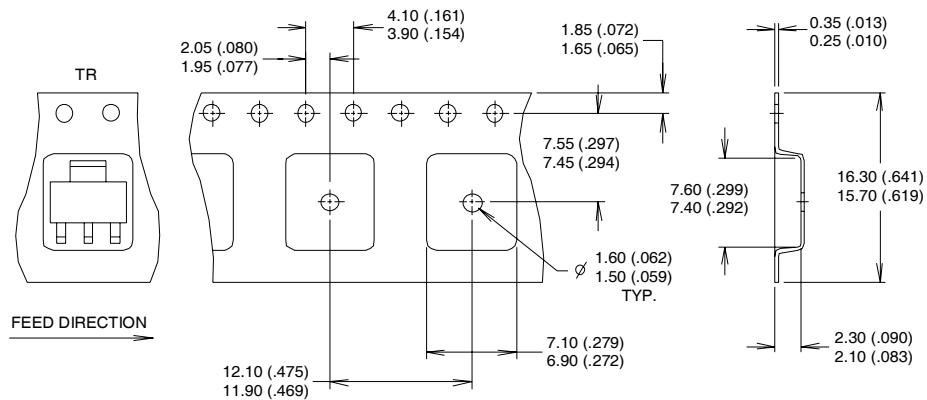HEXFET PRODUCT MARKING

EXAMPLE: THIS IS AN IRFL014

INTERNATIONAL RECTIFIER LOGO

FL014
I⊕R 314P

PART NUMBER

DATE CODE
(YYWW)
YY = YEAR
WW = WEEK
P = DESIGNATES LEAD-FREE
PRODUCT (OPTIONAL)

TOP

LOT CODE

AXXXX

A = ASSEMBLY SITE
CODE

BOTTOM

Notes:
1. For an Automotive Qualified version of this part please see http://www.irf.com/product-info/auto/
2. For the most current drawing please refer to IR website at http://www.irf.com/package/

IRFL024ZPbF

SOT-223 (TO-261AA) Tape & Reel Information

Dimensions are shown in milimeters (inches)

TR

FEED DIRECTION

2.05 (.080)
1.95 (.077)

4.10 (.161)
3.90 (.154)

1.85 (.072)
1.65 (.065)

7.55 (.297)
7.45 (.294)

0.35 (.013)
0.25 (.010)

7.60 (.299)
7.40 (.292)

16.30 (.641)
15.70 (.619)

ø 1.60 (.062)
1.50 (.059)
TYP.

7.10 (.279)
6.90 (.272)

2.30 (.090)
2.10 (.083)

12.10 (.475)
11.90 (.469)

NOTES :
1. CONTROLLING DIMENSION: MILLIMETER.
2. OUTLINE CONFORMS TO EIA-481 & EIA-541.
3. EACH ø330.00 (13.00) REEL CONTAINS 2,500 DEVICES.

13.20 (.519)
ø 12.80 (.504)

ø 330.00
(13.000)
MAX.

15.40 (.607)
11.90 (.469)
④

ø 50.00 (1.969)
MIN.

18.40 (.724)
MAX.
④

14.40 (.566)
12.40 (.488)
③

NOTES :
1. OUTLINE COMFORMS TO EIA-418-1.
2. CONTROLLING DIMENSION: MILLIMETER..
③ DIMENSION MEASURED @ HUB.
④ INCLUDES FLANGE DISTORTION @ OUTER EDGE.

Data and specifications subject to change without notice.
This product has been designed for the Industrial market.
Qualification Standards can be found on IR's Web site.